

**Synthesis of multiple fault oriented test groups from single fault test sets [Electronic resource]**

**Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan** 2013 8th International Conference on Design & Technology of Integrated Systems in Nanoscale Era (DTIS) : 26-28 March 2013, Abu Dhabi, UAE 2013 / p. 36-41 : ill [CD-ROM]